

ABSTRACT

A method for refining a length of a scan line, where the scan line is produced from a facet of a scanning device. The method comprises the steps of: (a) acquiring a plurality of scan line lengths produced from the facet, (b) determining from the plurality of scan line lengths, an average scan line length for the facet, and (c) determining from the average scan line length, a scan line length correction for the facet. A method for measuring a length of a scan line comprises the steps of: (a) charging an electrical current integrator to a voltage while a scan line is produced from a facet, (b) measuring the voltage, and (c) determining from the voltage, the length of the scan line produced from the facet.